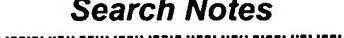


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/772,141	LEE, HEON	
	Examiner Paul A. Budd	Art Unit 2815	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner